

# ITC55600C

unclamped inductive load tester



## overview

Model ITC55600C is the high current (600A) version of the ITC55100C tester. The ITC55600 performs the same tests as the ITC55100C and includes Crowbar, WSS, and many features that improve testing accuracy, test results collection, test results viewing, and multiple tester networking.

Model ITC55600C performs ruggedness testing of power MOSFETs, discretes and modules and IGBTs, discretes and modules. It also tests single and dual diodes, and forward and reverse bias of IGBTs when used with an optional ITC55-RSF Output Selector Box.

The ITC55600C performs several types of tests that conform to MIL-STD-750C Method 3470. Method 3470 tests the capability of N-Channel MOSFETs and IGBTs by stressing them to controlled energy levels. This is accomplished by the devices driving an unclamped inductive load.

## test modes

- Single-Pulse Unclamped Inductive Switching (UIS)
- Single-Pulse Avalanche Stress (EAS)
- Repetitive Avalanche Energy (EAR)
- Repetitive Pulse to Failure (RPF)

## test performed

- Continuity test of device socket and/or contacts
- DC zero gate bias Drain-to-Source leakage test - pre and post avalanche
- Functional device test
- Avalanche test

## features

- Single Device Testing
- N channel only
- All Solid State Switching – No Relays
- EAR 1 Million pulses
- Timing Resolution of 40ns
- Current Range: 200A to 600A in 1A Steps. 401A to 600A in 1A steps with a Tolerance of +/- 1A.
- Avalanche Voltage to 2500V
- Bipolar Gate Drive with 28V swing
- Crowbar function
- WSS remote sensing
- New High Efficiency Kelvin Circuit
- Touch-Screen Program Entry/Control
- Waveform Capture/Display
- Internal Test Program Storage (20 files)
- Network capable software
- High Speed Inductor Charging, Reduces Test Time
- Programmable Leakage Test Voltage
- Pre/Post Avalanche Leakage Test
- Avalanche Collapse Test
- Versatile Test Handler Control
- Up to 15 Hardware Sort Bins
- Improved Voltage/Current Accuracy
- Software Updates via Flash Download
- Password Control of Parameter Entry
- Operates with all ITC Inductor Load Boxes
- Interfaces with ITC55MUX4 & ITC55-RSF
- Simple, Complete User Calibration
- Built-in Self Test

## safety features

- Test time-out
- Excessive leakage shutdown
- External safety lockout
- Two parallel connected Manual Start push buttons
- Device currents are constantly monitored. Testing is terminated if currents exceed or fail to reach programmable levels in a specified or calculated time.

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## available interfaces

- IEEE 488 GPIB control interface
- ITC5510 compatible 5-bin handler control interface
- 15 bin handler control interface for improved sorting of failures for process control analysis available options

## available options

- External Inductor Boxes:  
Several models of External Inductor Boxes are available:
  - ITC5514A: Manually selected inductance: 0.01 to 159.9mH (200A/2500V)
  - ITC5514B: Automatically selected inductance: 0.01 to 159.9mH (200A/2500V)
  - ITC5515: Automatically selected inductance: 0.1, 0.3, 1.0, 3.0 and 10mH (200A/2500V)
  - ITC5516: Automatically selected inductance: 0.001 to 0.300mH (600A/2500V)
  - ITC55140: Automatically selected, high speed switching, inductance: 0.01 to 159.9mH (200A/1500V)
  - ITC5517: Automatically selected inductance: 0.01 to 79.9mH (200A/2500V)
  - ITC55170: Automatically selected, high speed switching, inductance: 0.01 to 79.9mH (200A/1500V)
  - ITC55190: Automatically selected, Customize 10 Fix Inductances (400A/1500V)
- ITC55-RSF Output Selector Box allows the ITC55100 Testers to test various configurations of MOSFETs, IGBTs, and dual and single diodes without having to replacing the DUT fixture up to 1500V avalanche voltage.
- ITC55HVD2 (High Voltage Diode Interface Box) - The ITC55HVD2 is a high voltage avalanche interface adapter box option for testing diodes using the ITC55100 at voltages up to 2500V
- ITC55X00-DTF DUT Test Fixture with a known good “golden” DUT installed and with ITC factory test results so the ITC55x00 tester can be verified for correct and accurate operation.
- ITC Multiplexers Dual and Quad Die Testing
- ITC55X00 HNDIF Interface between ITC55X00 UIS Tester and handlers test contacts or Manual test fixtures
- ITC-MTF-55HV-2017- Manual Test Fixture, Dual Die with plug-in socket boards

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